



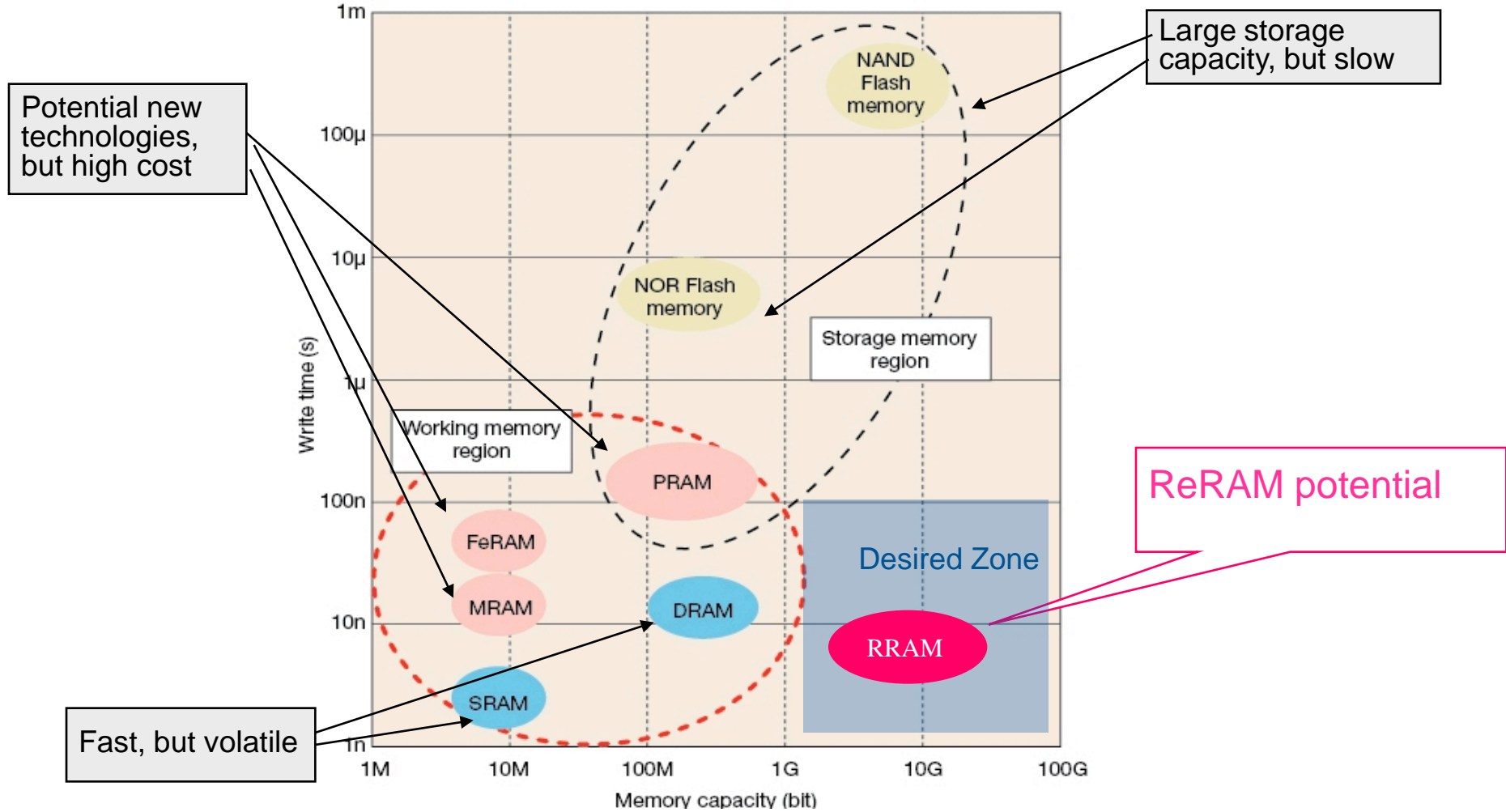
MOHJO™

**Metal Oxide Hetero Junction Operation
Nonvolatile Memory**

Lee Cleveland

Director of Device Engineering

4DS, Inc.

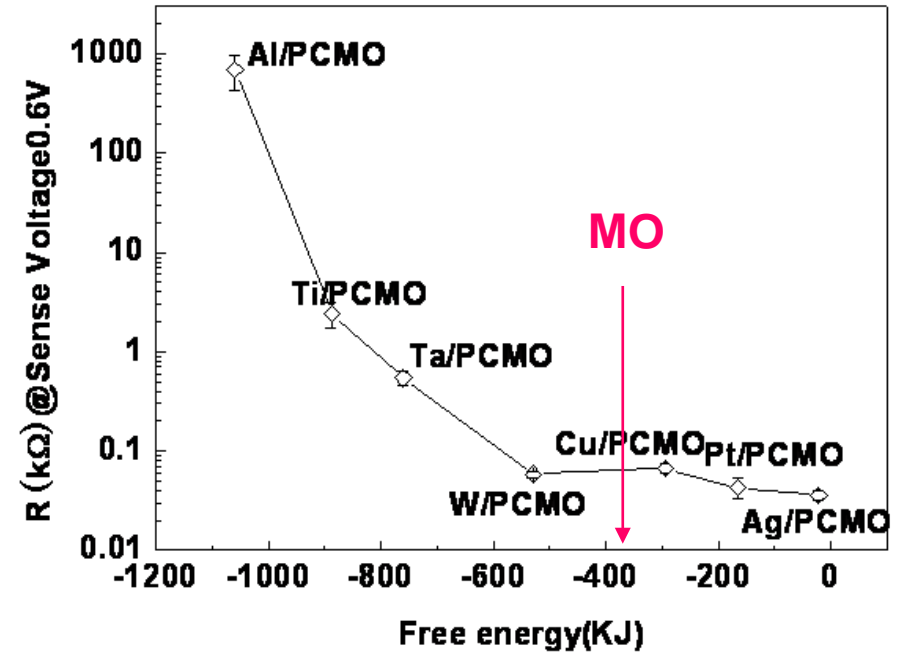
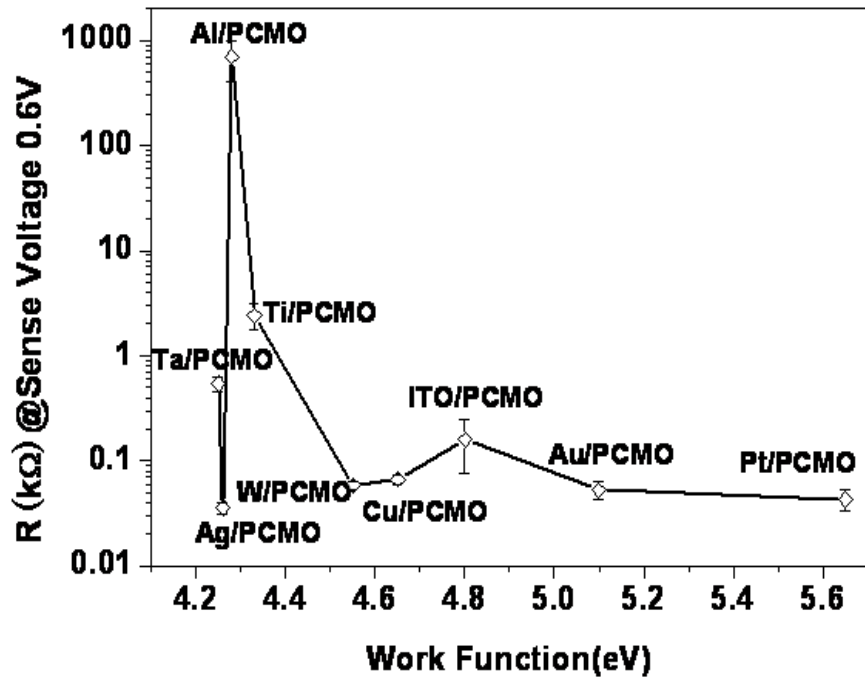


Role of Electrode Materials in Bipolar Resistive Switching Devices

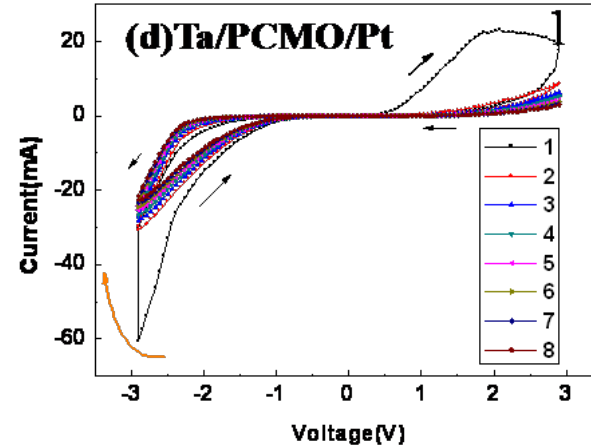
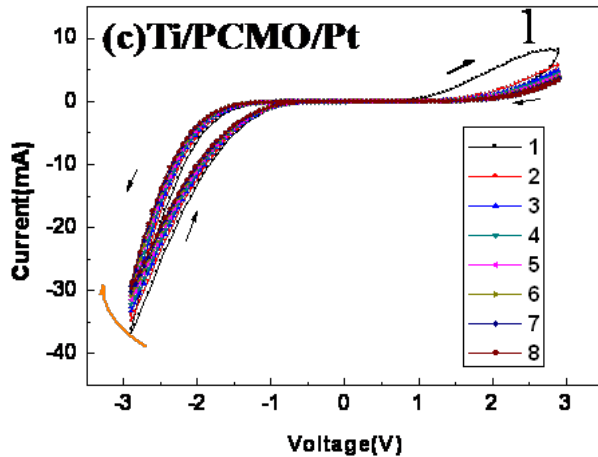
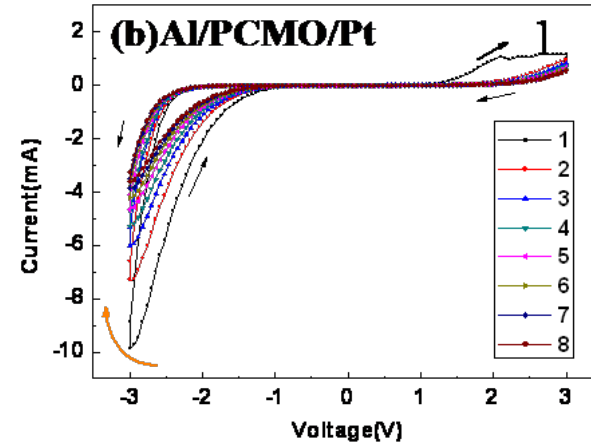
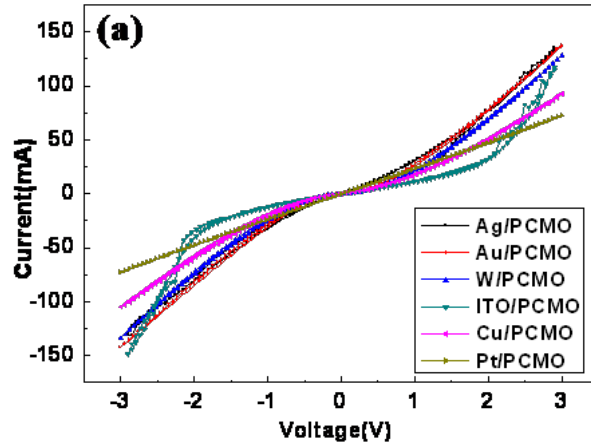


Classification of MOHJO devices

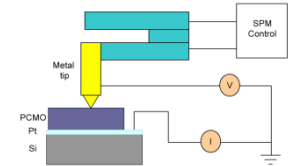
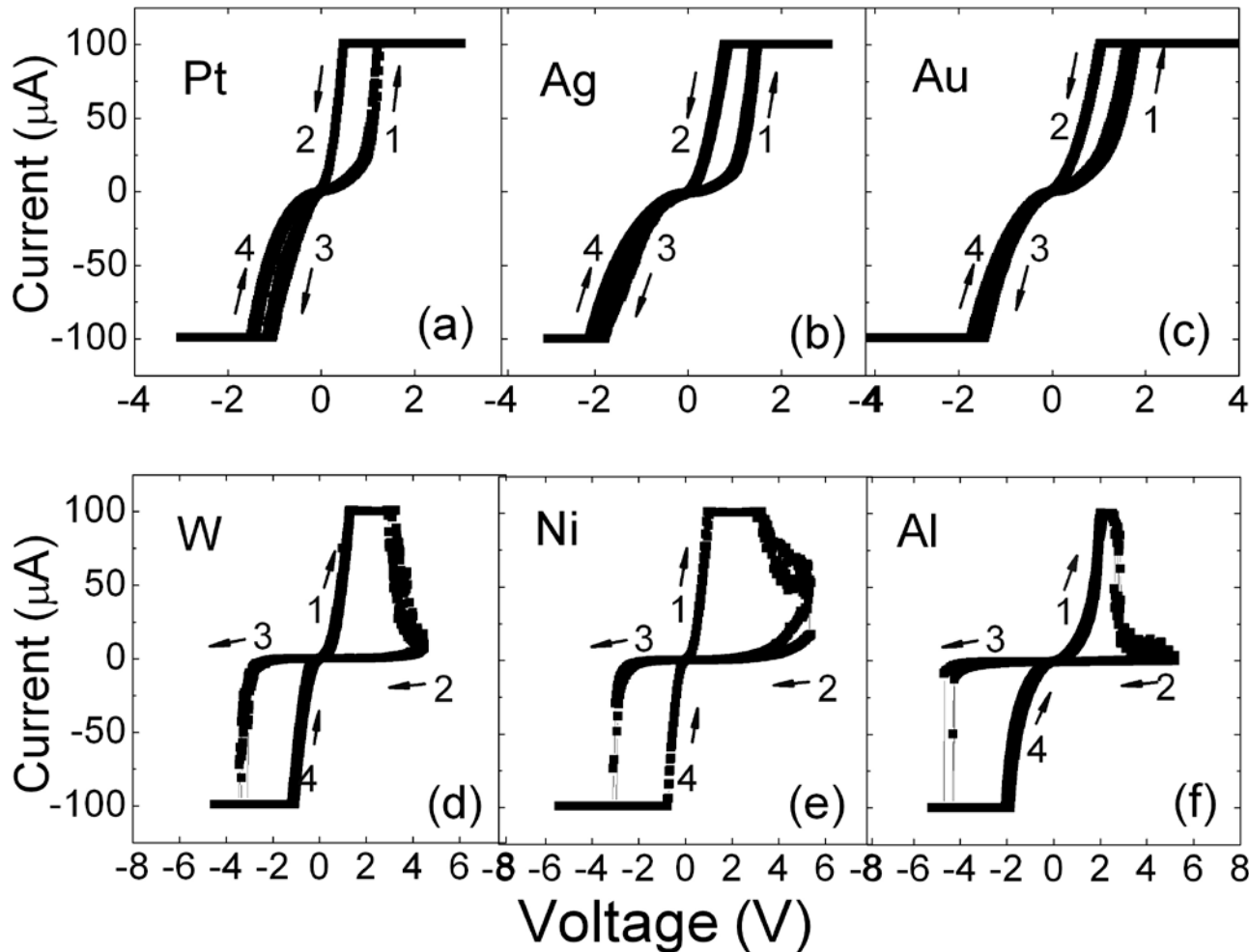
	Free energy	Device Structure
Type - I	$> \text{MOHJO}$	M/MO/M
Type - II	$< \text{MOHJO}$	M/MO/MO/M



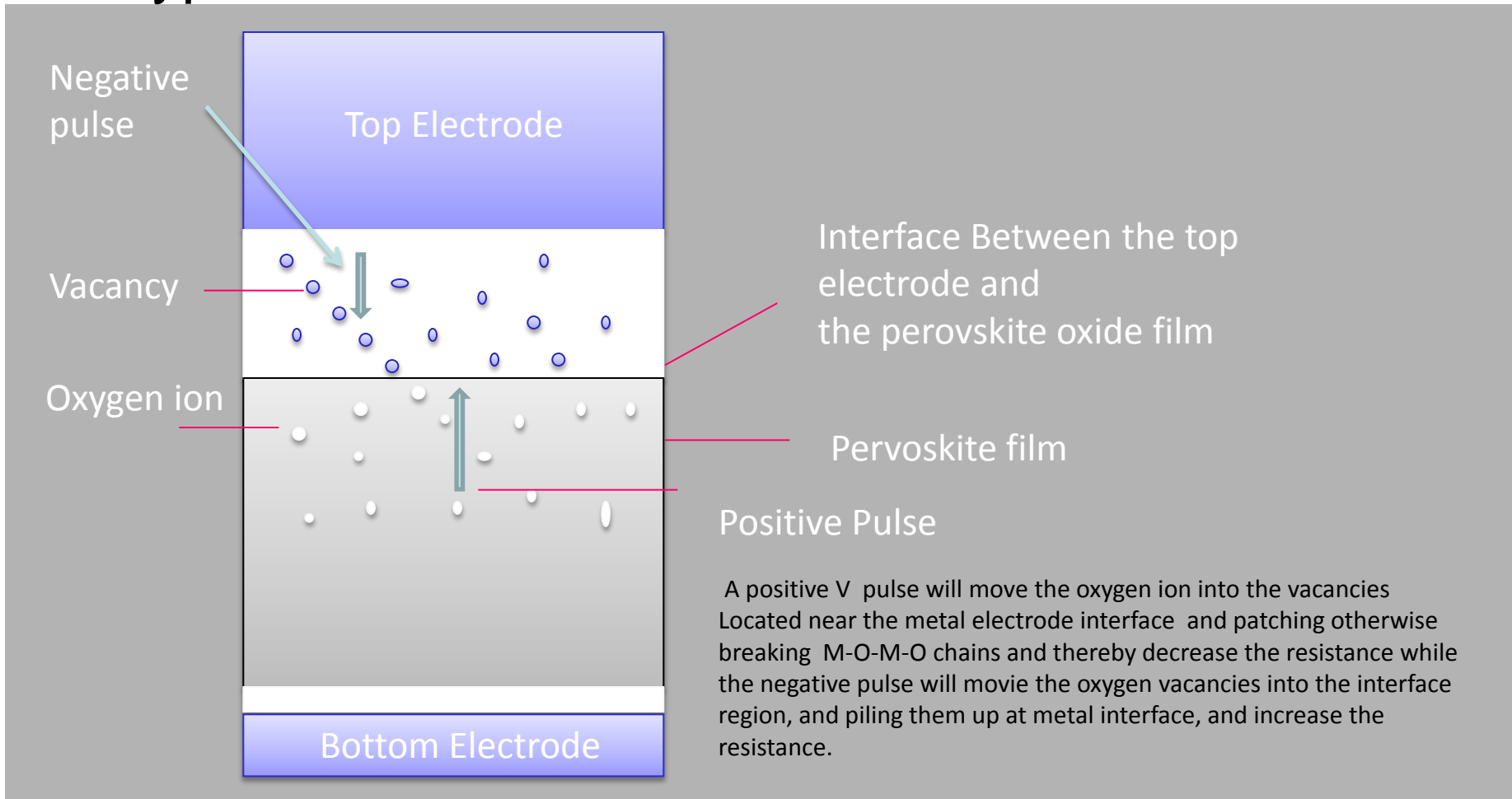
I-V Loop

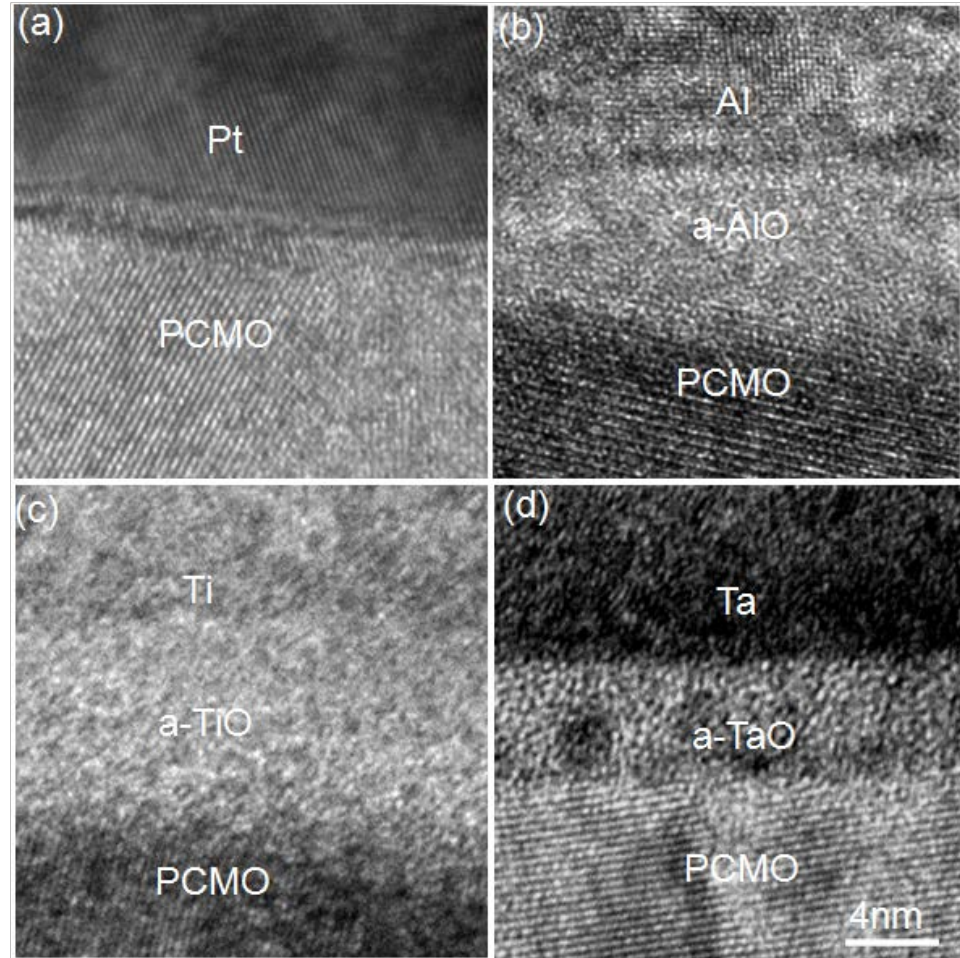
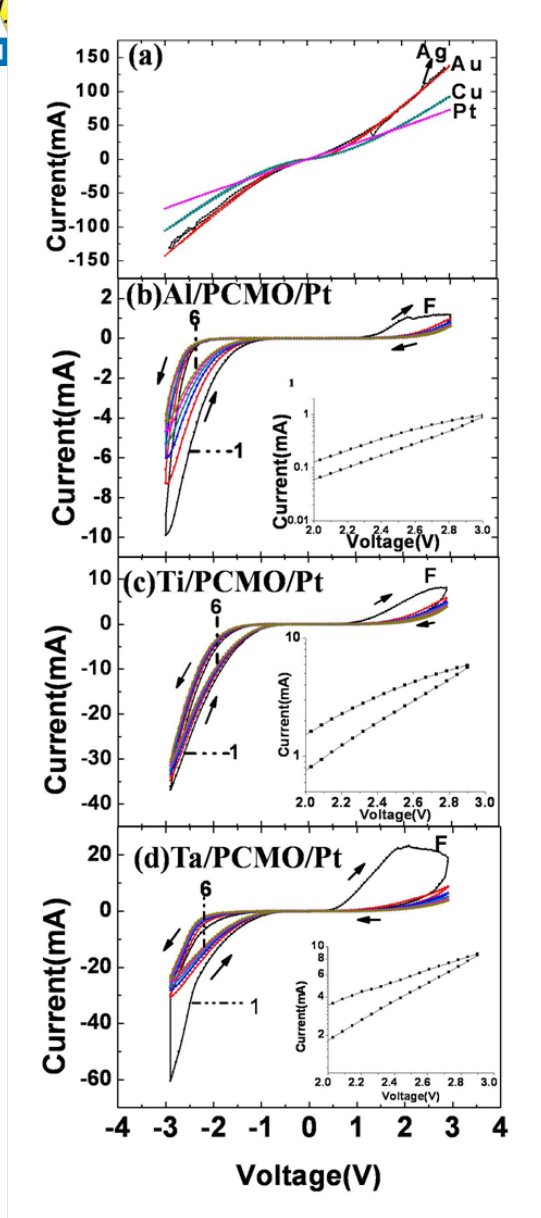


Clock vs Counter Clockwise Loop

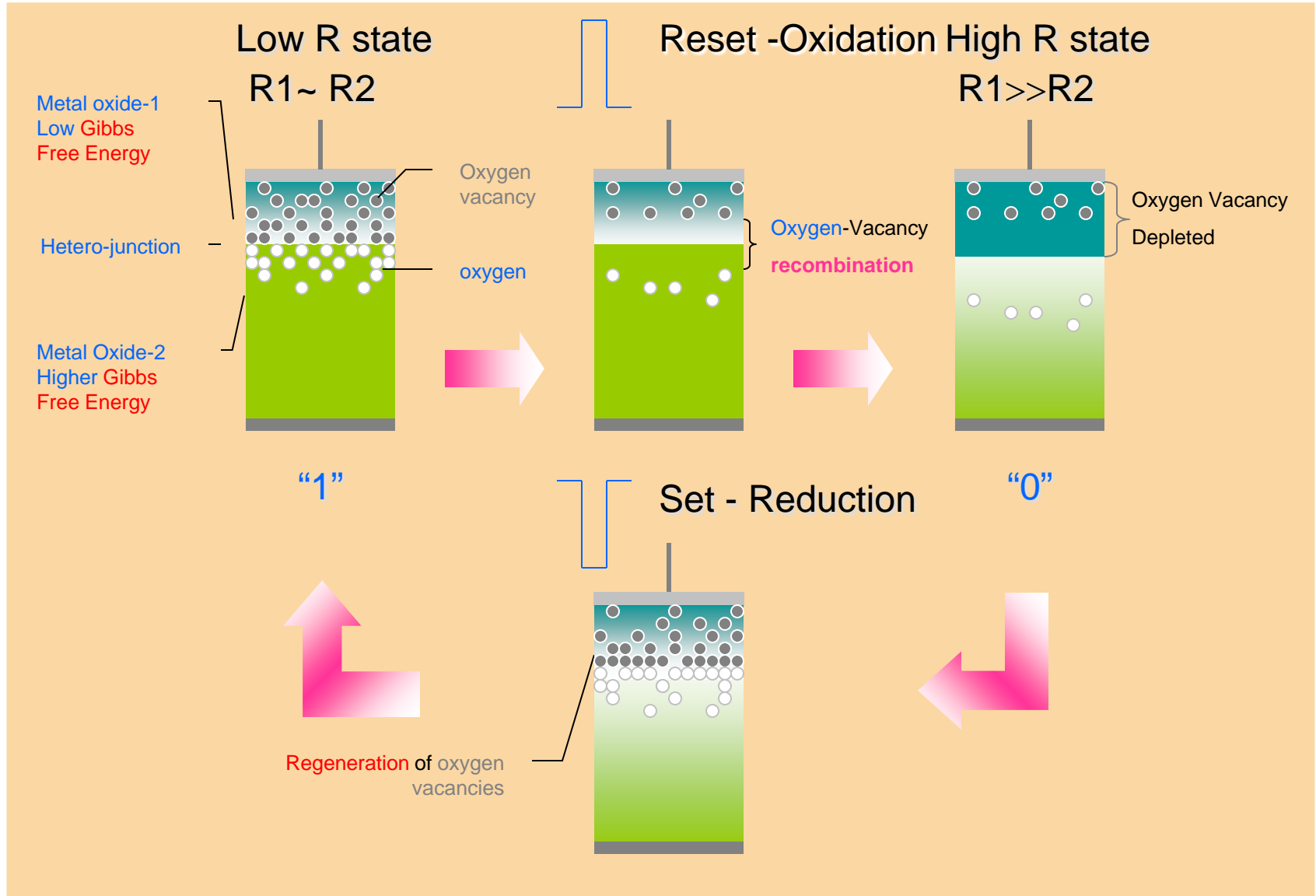


Type-I device: PCMO with non-reactive metal TE

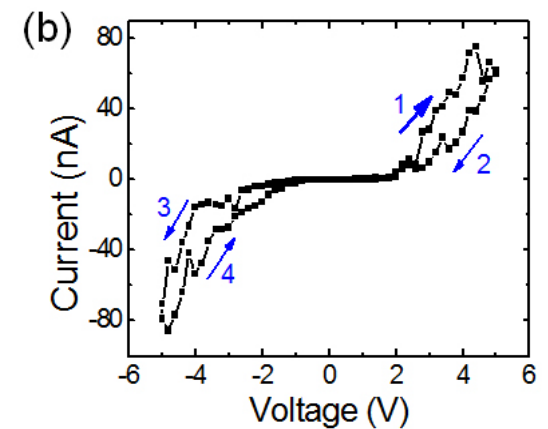
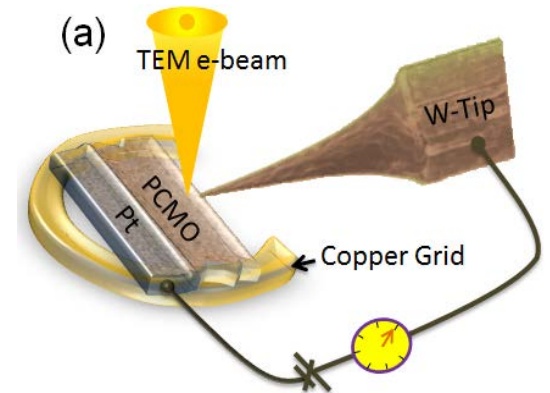
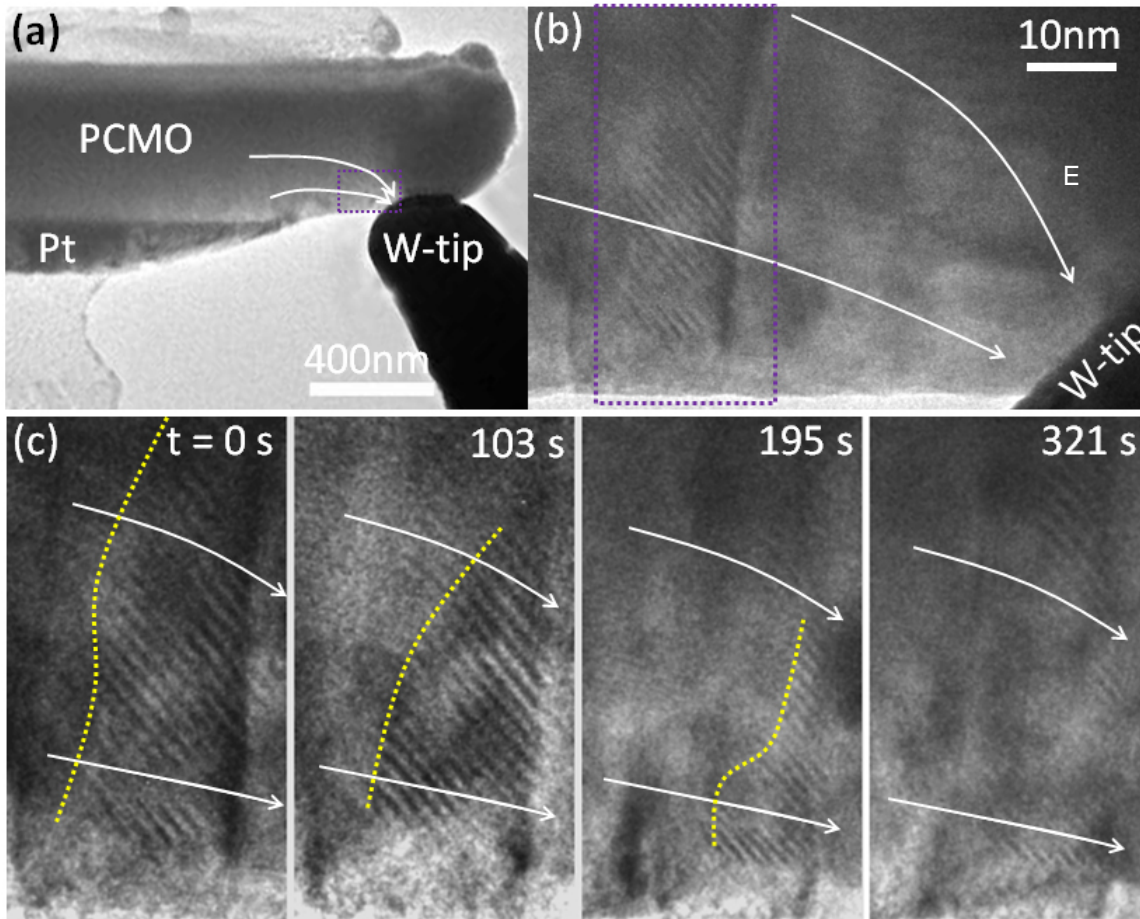


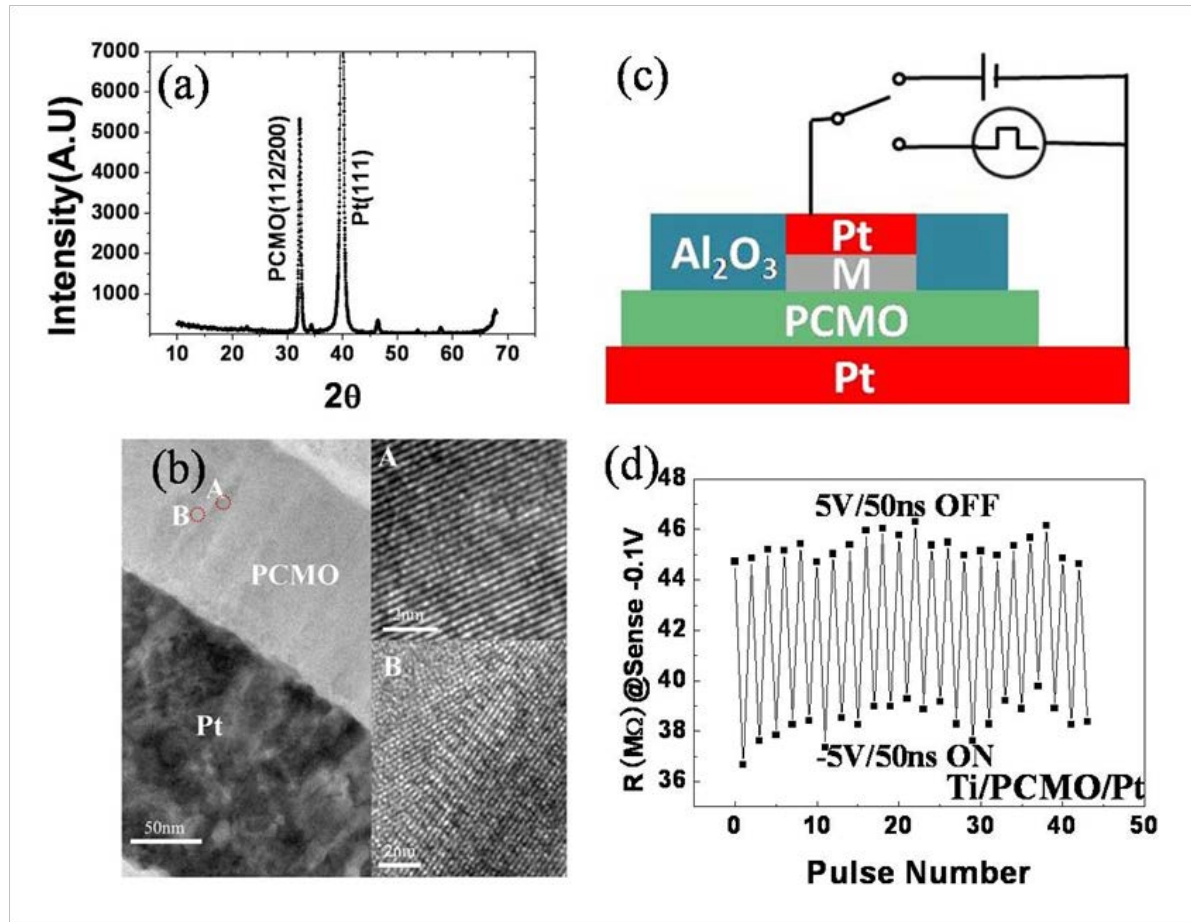


Type -II device: Metal Oxide Heterojunction Operation



In situ TEM Observation of Oxygen Vacancy Motion





4DS proprietary process yields columnar polycrystalline PCMO which is fully CMOS compatible & high throughput

Metal Oxide Heterojunction	P-N Junction
Gibbs Energy	Fermi energy
Space vacancy formation	Space charge formation
Ion migration	Charge drift
Field and temperature sensitive	Field and temperature sensitive
Metastable or Chemical reaction	Field dependent

Characteristics of MOHJO devices

	TYPE-I	TYPE-II
ΔR	Small	Large
Response time	fast	fast
Retention	Good	Excellent
Endurance	Good	Good
Tunable	Poor	Excellent